

# FEI Tecnai 20 TEM

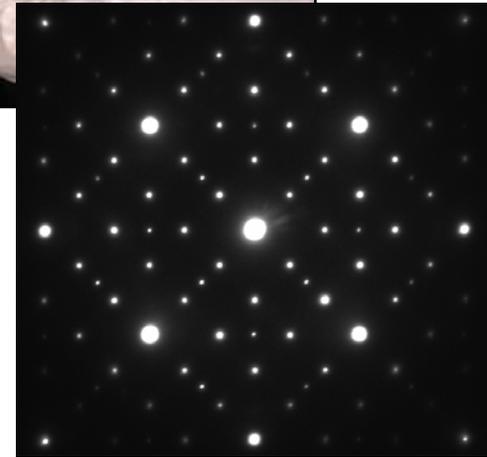
## Techniques/Capabilities:

- Conventional TEM and AEM
- Digital Image Acquisition
- Digital Video
- High-tilt stage
- EDS



## Current Research Activities:

Conventional TEM experiments involving defect analysis, selected area or convergent beam electron diffraction, hollow cone illumination, light element EDS, and *in situ* heating.



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